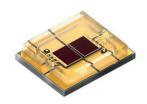
# LE A Q7WP

## **OSRAM OSTAR® Projection Compact**

Compact light source in SMT technology, glass window on top, RoHS compliant











## **Applications**

- Head-Up Display LED & Laser
- Projection Home LED & Laser

- Projection Professional LED & Laser
- Stage Lighting (LED & Laser)

#### Features:

- Package: compact lightsource in SMT technology with glass window on top
- Chip technology: Thinfilm
- Typ. Radiation: 120° (Lambertian emitter)
- Color: λ<sub>dom</sub> = 617 nm (• amber)
- Corrosion Robustness Class: 3B
- ESD: 2 kV acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 2)

## **Ordering Information**

Туре	Luminous Flux $^{1)}$ $I_F = 1400 \text{ mA}$ $\Phi_V$	Ordering Code	
LE A Q7WP-NXPX-23	280 520 lm	Q65111A8289	



## LE A Q7WP

Maximum Ratings			
Parameter	Symbol		Values
Operating Temperature	T <sub>op</sub>	min.	-40 °C
	op.	max.	105 °C
Storage Temperature	T <sub>stg</sub>	min.	-40 °C
	otg	max.	105 °C
Junction Temperature	T <sub>j</sub>	max.	125 °C
Forward Current	I <sub>F</sub>	min.	40 mA
T <sub>S</sub> = 25 °C; per chip		max.	5000 mA
Forward Current pulsed D = 0.5; f = 120 Hz; T <sub>s</sub> = 25 °C; per chip	I <sub>F pulse</sub>		6000 mA
ESD withstand voltage acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 2)	$V_{ESD}$		2 kV
Reverse current 2)	I <sub>R</sub>	max.	200 mA



# **Characteristics**

 $I_F$  = 1400 mA;  $T_S$  = 25 °C; per chip

Parameter	Symbol		Values
Peak Wavelength	$\lambda_{\sf peak}$	typ.	624 nm
Dominant Wavelength 3)	$\lambda_{\sf dom}$	min. typ. max.	612 nm 617 nm 624 nm
Spectral bandwidth at 50% I <sub>rel,max</sub>	$\Delta \lambda$	typ.	18 nm
Viewing angle at 50% I <sub>v</sub>	2φ	typ.	120 °
Radiating surface	$A_{color}$	typ.	1.54 x 2.59 mm²
Partial Flux acc. CIE 127:2007 <sup>4)</sup> I <sub>F</sub> = 1400 mA	Ф <sub>Е/V, 120°</sub>	typ.	0.82
Forward Voltage <sup>5)</sup> I <sub>F</sub> = 1400 mA; per Chip	V <sub>F</sub>	min. typ. max.	2.00 V 2.20 V 2.90 V
Reverse voltage (ESD device)	$V_{\text{R ESD}}$	min.	45 V
Reverse voltage <sup>2)</sup> I <sub>R</sub> = 20 mA	$V_R$	max.	1.2 V
Real thermal resistance junction/solderpoint <sup>6)</sup>	$R_{thJS\ real}$	typ. max.	1.00 K / W 1.30 K / W
Electrical thermal resistance junction/solderpoint $^{\rm 6)}$ with efficiency $\eta_{\rm e}$ = 25 $\%$	$R_{ ext{thJS elec.}}$	typ. max.	0.75 K / W 0.98 K / W



# **Brightness Groups**

Group	Luminous Flux <sup>1)</sup> $I_F = 1400 \text{ mA}$ min. $\Phi_V$	Luminous Flux <sup>1)</sup> $I_F = 1400 \text{ mA}$ max. $\Phi_V$
NX	280 lm	330 lm
NY	330 lm	390 lm
NZ	390 lm	450 lm
PX	450 lm	520 lm

# **Wavelength Groups**

Group	Dominant Wavelength 3)	Dominant Wavelength 3)
	min.	max.
	$\lambda_{ ext{dom}}$	$\lambda_{dom}$
2	612 nm	618 nm
3	618 nm	624 nm

# **Group Name on Label**

Example: NX-2

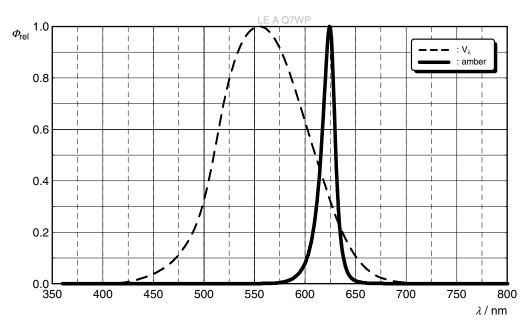
Brightness Wavelength

NX 2



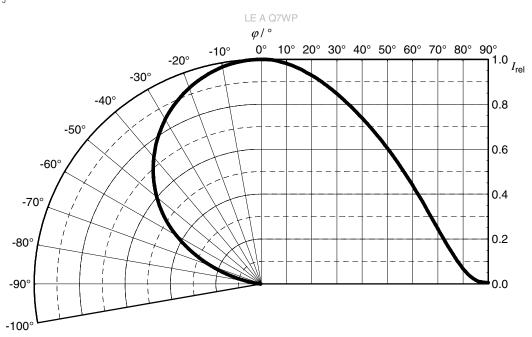
## Relative Spectral Emission 4)

 $\Phi_{\rm rel}$  = f ( $\lambda$ ); I $_{\rm F}$  = 1400 mA; per Chip; T $_{\rm J}$  = 25 °C



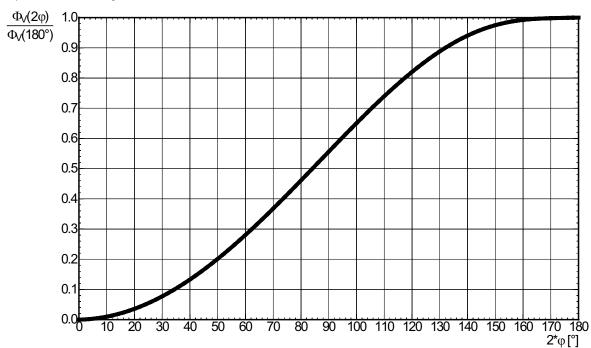
## Radiation Characteristics 4)

$$I_{rel} = f(\phi); T_J = 25 °C$$



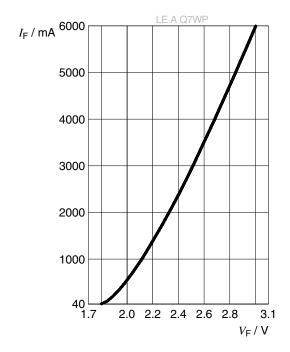
## Relative Partial Flux 4)

 $\Phi_{V}(2\phi)/\Phi_{V}(180^{\circ}) = f(\phi); T_{J} = 25 {\circ}C$ 



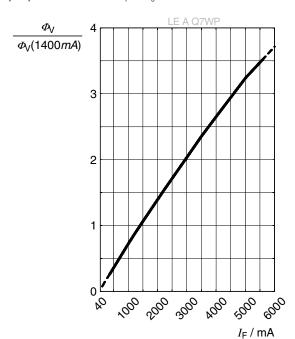
## Forward current 4), 7)

 $I_F = f(V_F); T_J = 25 °C; per Chip$ 



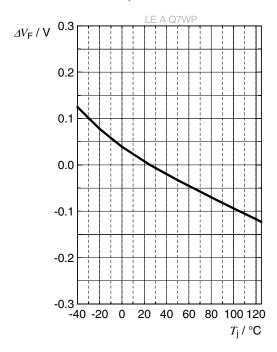
## Relative Luminous Flux 4), 7)

 $\Phi_{V}/\Phi_{V}(1400 \text{ mA}) = f(I_{F}); T_{J} = 25 \text{ °C}; per Chip}$ 



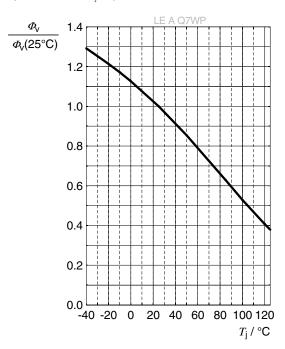
## Forward Voltage 4)

 $\Delta V_{_F} = V_{_F} - V_{_F} (25~^{\circ}\text{C}) = f(T_{_j}); I_{_F} = 1400~\text{mA}; per Chip}$ 



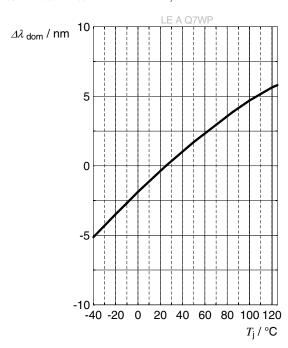
### Relative Luminous Flux 4)

 $\Phi_{v}/\Phi_{v}(25~^{\circ}\text{C}) = f(T_{i}); I_{F} = 1400~\text{mA}; per Chip}$ 



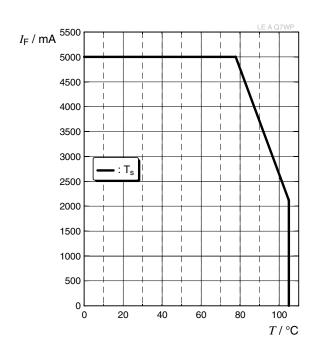
# **Dominant Wavelength** 4)

 $\Delta\lambda_{\text{dom}} = \lambda_{\text{dom}} - \lambda_{\text{dom}} (25 \ ^{\circ}\text{C}) = f(T_{j}); \ I_{F} = 1400 \ \text{mA}; \ \text{per Chip}$ 



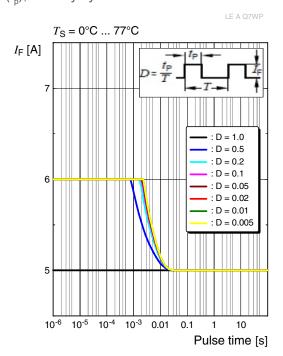
### Max. Permissible Forward Current

 $I_F = f(T)$ 



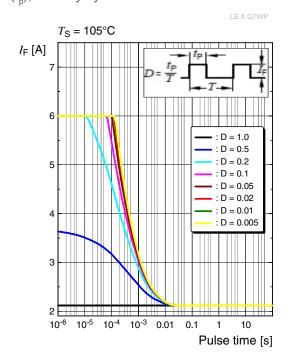
## **Permissible Pulse Handling Capability**

 $I_F = f(t_p)$ ; D: Duty cycle



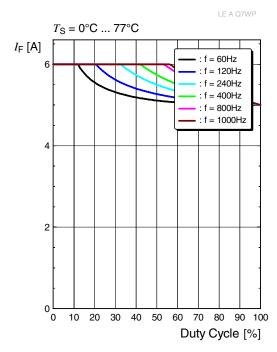
# **Permissible Pulse Handling Capability**

 $I_F = f(t_p)$ ; D: Duty cycle



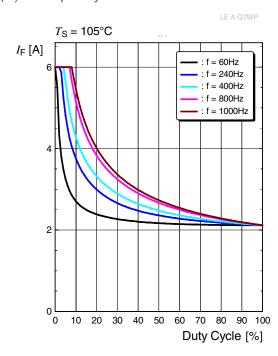
# Permissible F. Handling Capability

I<sub>F</sub>=f(D) f: Frequency



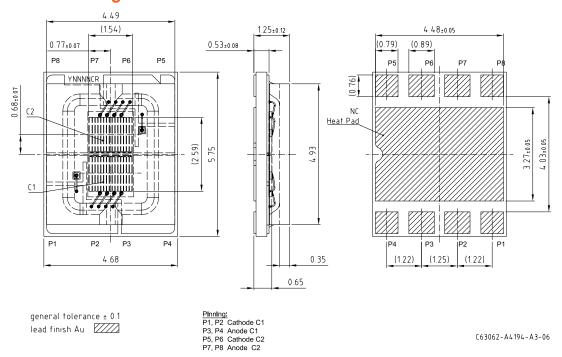
# Permissible F. Handling Capability

I<sub>F</sub>=f(D) f: Frequency





## **Dimensional Drawing** 8)



#### **Further Information:**

**Approximate Weight:** 96.0 mg

Package marking: Cathode

**Corrosion test:** Class: 3B

Test condition: 40°C / 90 % RH / 15 ppm H<sub>2</sub>S / 14 days (stricter than IEC

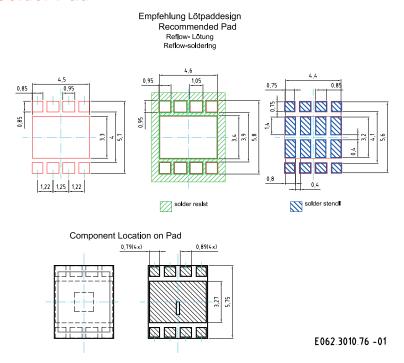
60068-2-43)

**ESD** advice: The device is protected by ESD device which is connected in parallel to the

Chip.



### Recommended Solder Pad 8)



Do not use exposed copper MCPCB technology for automotive applications. For superior solder joint connectivity results we recommend soldering under standard nitrogen atmosphere. Package not suitable for any kind of wet cleaning or ultrasonic cleaning.

## **Reflow Soldering Profile**

Product complies to MSL Level 2 acc. to JEDEC J-STD-020E



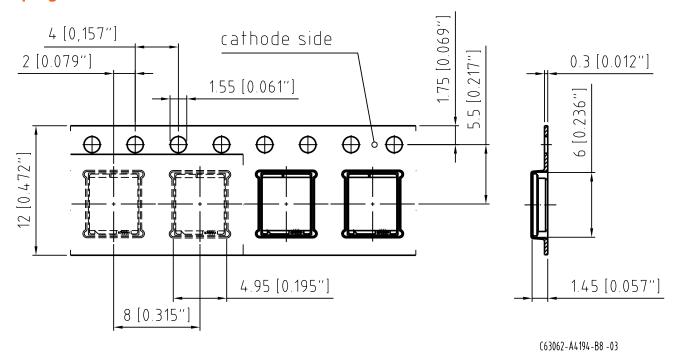
Profile Feature	Symbol	Pb-Free (SnAgCu) Assembly			Unit
		Minimum	Recommendation	Maximum	
Ramp-up rate to preheat*)			2	3	K/s
25 °C to 150 °C					
Time t <sub>s</sub>	$t_s$	60	100	120	S
$T_{Smin}$ to $T_{Smax}$					
Ramp-up rate to peak*)			2	3	K/s
$T_{Smax}$ to $T_{P}$					
Liquidus temperature	$T_L$		217		°C
Time above liquidus temperature	$t_{\scriptscriptstyle \perp}$		80	100	S
Peak temperature	$T_{P}$		245	260	°C
Time within 5 °C of the specified peak	t <sub>P</sub>	10	20	30	S
temperature T <sub>P</sub> - 5 K					
Ramp-down rate*			3	6	K/s
T <sub>P</sub> to 100 °C					
Time				480	S
25 °C to T <sub>P</sub>					

All temperatures refer to the center of the package, measured on the top of the component

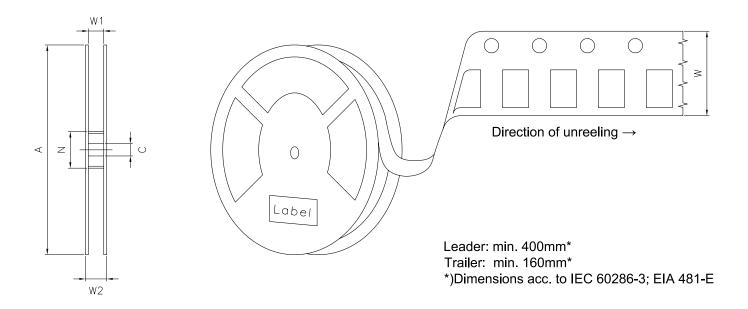


<sup>\*</sup> slope calculation DT/Dt: Dt max. 5 s; fulfillment for the whole T-range

# Taping 8)



# Tape and Reel 9)



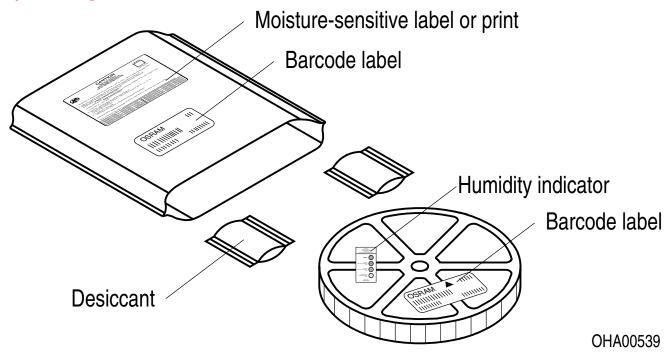
## **Reel Dimensions**

Α	W	$N_{\min}$	W <sub>1</sub>	$W_{2max}$	Pieces per PU
180 mm	12 + 0.3 / - 0.1 mm	60 mm	12.4 + 2 mm	18.4 mm	1000

### **Barcode-Product-Label (BPL)**



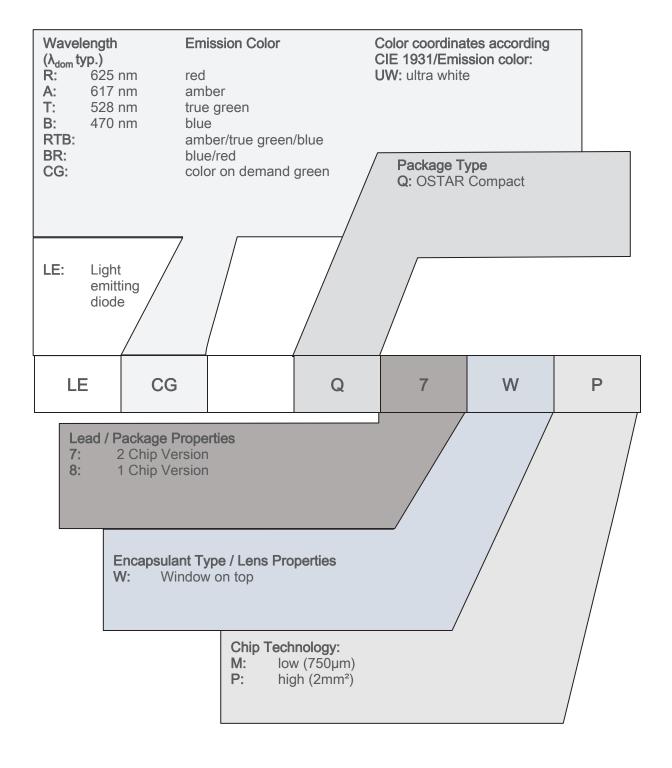
## Dry Packing Process and Materials 8)



Moisture-sensitive product is packed in a dry bag containing desiccant and a humidity card according JEDEC-STD-033.



## **Type Designation System**





#### **Notes**

The evaluation of eye safety occurs according to the standard IEC 62471:2006 (photo biological safety of lamps and lamp systems). Within the risk grouping system of this IEC standard, the device specified in this data sheet falls into the class **exempt group (exposure time 10000 s)**. Under real circumstances (for exposure time, conditions of the eye pupils, observation distance), it is assumed that no endangerment to the eye exists from these devices. As a matter of principle, however, it should be mentioned that intense light sources have a high secondary exposure potential due to their blinding effect. When looking at bright light sources (e.g. headlights), temporary reduction in visual acuity and afterimages can occur, leading to irritation, annoyance, visual impairment, and even accidents, depending on the situation.

Subcomponents of this device contain, in addition to other substances, metal filled materials including silver. Metal filled materials can be affected by environments that contain traces of aggressive substances. Therefore, we recommend that customers minimize device exposure to aggressive substances during storage, production, and use. Devices that showed visible discoloration when tested using the described tests above did show no performance deviations within failure limits during the stated test duration. Respective failure limits are described in the IEC60810.

For further application related information please visit www.osram-os.com/appnotes



#### **Disclaimer**

#### Attention please!

The information describes the type of component and shall not be considered as assured characteristics. Terms of delivery and rights to change design reserved. Due to technical requirements components may contain dangerous substances.

For information on the types in question please contact our Sales Organization.

If printed or downloaded, please find the latest version on the OSRAM OS website.

#### **Packing**

Please use the recycling operators known to you. We can also help you – get in touch with your nearest sales office. By agreement we will take packing material back, if it is sorted. You must bear the costs of transport. For packing material that is returned to us unsorted or which we are not obliged to accept, we shall have to invoice you for any costs incurred.

#### Product and functional safety devices/applications or medical devices/applications

OSRAM OS components are not developed, constructed or tested for the application as safety relevant component or for the application in medical devices.

OSRAM OS products are not qualified at module and system level for such application.

In case buyer – or customer supplied by buyer – considers using OSRAM OS components in product safety devices/applications or medical devices/applications, buyer and/or customer has to inform the local sales partner of OSRAM OS immediately and OSRAM OS and buyer and /or customer will analyze and coordinate the customer-specific request between OSRAM OS and buyer and/or customer.



#### Glossary

- Brightness: Brightness values are measured during a current pulse of typically 25 ms, with an internal reproducibility of ±8 % and an expanded uncertainty of ±11 % (acc. to GUM with a coverage factor of k = 3).
- Reverse Operation: This product is intended to be operated applying a forward current within the specified range. Applying any continuous reverse bias or forward bias below the voltage range of light emission shall be avoided because it may cause migration which can change the electro-optical characteristics or damage the LED.
- Wavelength: The wavelength is measured at a current pulse of typically 25 ms, with an internal reproducibility of ±0.5 nm and an expanded uncertainty of ±1 nm (acc. to GUM with a coverage factor of k =
- Typical Values: Due to the special conditions of the manufacturing processes of semiconductor devices, the typical data or calculated correlations of technical parameters can only reflect statistical figures. These do not necessarily correspond to the actual parameters of each single product, which could differ from the typical data and calculated correlations or the typical characteristic line. If requested, e.g. because of technical improvements, these typ. data will be changed without any further notice.
- Forward Voltage: The forward voltage is measured during a current pulse of typically 8 ms, with an internal reproducibility of ±0.05 V and an expanded uncertainty of ±0.1 V (acc. to GUM with a coverage factor of k = 3).
- 6) **Thermal Resistance:** Rth max is based on statistic values (6σ).
- Characteristic curve: In the range where the line of the graph is broken, you must expect higher differences between single devices within one packing unit.
- Tolerance of Measure: Unless otherwise noted in drawing, tolerances are specified with ±0.1 and dimensions are specified in mm.
- Tape and Reel: All dimensions and tolerances are specified acc. IEC 60286-3 and specified in mm.



#### LE A Q7WP

Revision History				
Version	Date	Change		
1.7	2018-11-28	Characteristics Electro - Optical Characteristics (Diagrams)		
1.9	2020-06-03	Schematic Transportation Box Dimensions of Transportation Box		



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